International
IOR Rectifier

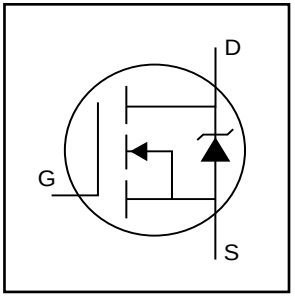
PD - 9.1333B

PRELIMINARY

IRLR/U3103

HEXFET® Power MOSFET

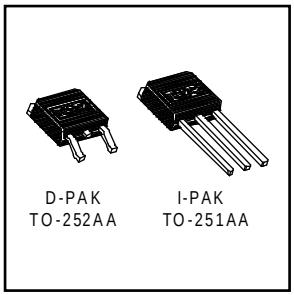
- Logic-Level Gate Drive
- Ultra Low On-Resistance
- Surface Mount (IRLR3103)
- Straight Lead (IRLU3103)
- Advanced Process Technology
- Fast Switching
- Fully Avalanche Rated



V_{DSS} = 30V

$R_{DS(on)}$ = 0.019Ω

I_D = 46A⑤



Description

Fifth Generation HEXFETs from International Rectifier utilize advanced processing techniques to achieve the lowest possible on-resistance per silicon area. This benefit, combined with the fast switching speed and ruggedized device design that HEXFET Power MOSFETs are well known for, provides the designer with an extremely efficient device for use in a wide variety of applications.

The D-PAK is designed for surface mounting using vapor phase, infrared, or wave soldering techniques. The straight lead version (IRFU series) is for through-hole mounting applications. Power dissipation levels up to 1.5 watts are possible in typical surface mount applications.

Absolute Maximum Ratings

	Parameter	Max.	Units
I_D @ T_C = 25°C	Continuous Drain Current, V_{GS} @ 10V	46⑤	A
I_D @ T_C = 100°C	Continuous Drain Current, V_{GS} @ 10V	29⑤	
I_{DM}	Pulsed Drain Current ①⑦	220	
P_D @T_C = 25°C	Power Dissipation	69	W
	Linear Derating Factor	0.56	W/°C
V_{GS}	Gate-to-Source Voltage	±16	V
E_{AS}	Single Pulse Avalanche Energy ②⑦	240	mJ
I_{AR}	Avalanche Current①⑦	34	A
E_{AR}	Repetitive Avalanche Energy①	6.9	mJ
dv/dt	Peak Diode Recovery dv/dt ③⑦	2.0	V/ns
T_J	Operating Junction and	-55 to + 150	°C
T_{STG}	Storage Temperature Range		
	Soldering Temperature, for 10 seconds	300 (1.6mm from case)	

Thermal Resistance

	Parameter	Min.	Typ.	Max.	Units
$R_{\theta JC}$	Junction-to-Case	——	——	1.8	°C/W
$R_{\theta JA}$	Junction-to-Ambient (PCB mount)**	——	——	50	
$R_{\theta JA}$	Junction-to-Ambient	——	——	110	

** When mounted on 1" square PCB (FR-4 or G-10 Material) .
For recommended footprint and soldering techniques refer to application note #AN-994

Electrical Characteristics @ T_J = 25°C (unless otherwise specified)

	Parameter	Min.	Typ.	Max.	Units	Conditions
$V_{(BR)DSS}$	Drain-to-Source Breakdown Voltage	30	—	—	V	V_{GS} = 0V, I_D = 250µA
$\Delta V_{(BR)DSS}/\Delta T_J$	Breakdown Voltage Temp. Coefficient	—	0.037	—	V/°C	Reference to 25°C, I_D = 1mA
$R_{DS(on)}$	Static Drain-to-Source On-Resistance	—	—	0.019	Ω	V_{GS} = 10V, I_D = 28A ④
		—	—	0.024		V_{GS} = 4.5V, I_D = 23A ④
$V_{GS(th)}$	Gate Threshold Voltage	1.0	—	—	V	V_{DS} = V_{GS}, I_D = 250µA
g_{fs}	Forward Transconductance	23	—	—	S	V_{DS} = 25V, I_D = 34A⑦
I_{DSS}	Drain-to-Source Leakage Current	—	—	25	µA	V_{DS} = 30V, V_{GS} = 0V
		—	—	250		V_{DS} = 24V, V_{GS} = 0V, T_J = 125°C
I_{GSS}	Gate-to-Source Forward Leakage	—	—	100	nA	V_{GS} = 16V
	Gate-to-Source Reverse Leakage	—	—	-100		V_{GS} = -16V
Q_g	Total Gate Charge	—	—	50	nC	I_D = 34A
Q_{gs}	Gate-to-Source Charge	—	—	14		V_{DS} = 24V
Q_{gd}	Gate-to-Drain ("Miller") Charge	—	—	28		V_{GS} = 4.5V, See Fig. 6 and 13 ④⑦
$t_{d(on)}$	Turn-On Delay Time	—	9.0	—	ns	V_{DD} = 15V
t_r	Rise Time	—	210	—		I_D = 34A
$t_{d(off)}$	Turn-Off Delay Time	—	20	—		R_G = 3.4Ω, V_{GS} = 4.5V
t_f	Fall Time	—	54	—		R_D = 0.43Ω, See Fig. 10 ④⑦
L_D	Internal Drain Inductance	—	4.5	—	nH	Between lead, 6mm (0.25in.) from package and center of die contact⑥
L_S	Internal Source Inductance	—	7.5	—		
C_{iss}	Input Capacitance	—	1600	—	pF	V_{GS} = 0V
C_{oss}	Output Capacitance	—	640	—		V_{DS} = 25V
C_{rss}	Reverse Transfer Capacitance	—	320	—		f = 1.0MHz, See Fig. 5⑦

Source-Drain Ratings and Characteristics

	Parameter	Min.	Typ.	Max.	Units	Conditions
I_S	Continuous Source Current (Body Diode)	—	—	46⑤	A	MOSFET symbol showing the integral reverse p-n junction diode.
I_{SM}	Pulsed Source Current (Body Diode) ①⑦	—	—	220⑤		
V_{SD}	Diode Forward Voltage	—	—	1.3	V	T_J = 25°C, I_S = 28A, V_{GS} = 0V ④
t_{rr}	Reverse Recovery Time	—	81	120	ns	T_J = 25°C, I_F = 34A
Q_{rr}	Reverse RecoveryCharge	—	210	310	nC	di/dt = 100A/µs ④⑦
t_{on}	Forward Turn-On Time	Intrinsic turn-on time is negligible (turn-on is dominated by L_S+L_D)				

Specification changes

Rev. #	Parameters	Old spec.	New spec.	Comments	Revision Date
1	$V_{GS(th)}$ (Max.)	2.5V	No spec.	Removed $V_{GS(th)}$ Max. Specification	5/1/96
1	V_{GS} (Max.)	±20	±16	Decrease V_{GS} Max. Specification	5/1/96

Notes:

① Repetitive rating; pulse width limited by max. junction temperature. (See fig. 11)

② V_{DD} = 15V, starting T_J = 25°C, L = 300µH R_G = 25Ω, I_{AS} = 34A. (See Figure 12)

③ I_{SD} ≤ 34A, di/dt ≤ 140A/µs, V_{DD} ≤ $V_{(BR)DSS}$, T_J ≤ 150°C

④ Pulse width ≤ 300µs; duty cycle ≤ 2%.

⑤ Caculated continuous current based on maximum allowable junction temperature; Package limitation current = 20A.

⑥ This is applied for I-PAK, L_S of D-PAK is measured between lead and center of die contact

⑦ Uses IRL3103 data and test conditions.

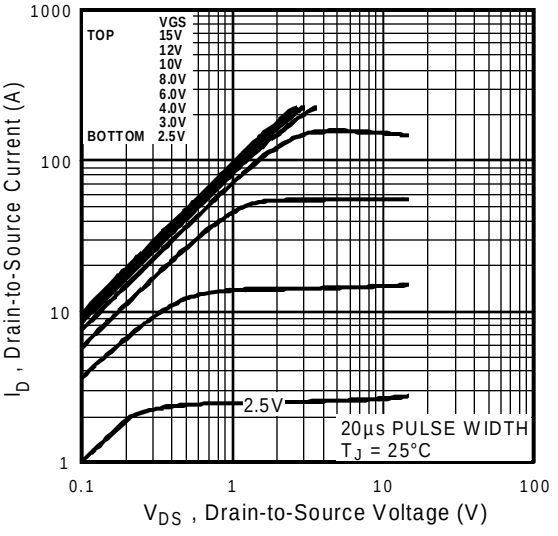


Fig 1. Typical Output Characteristics, $T_J = 25^oC$

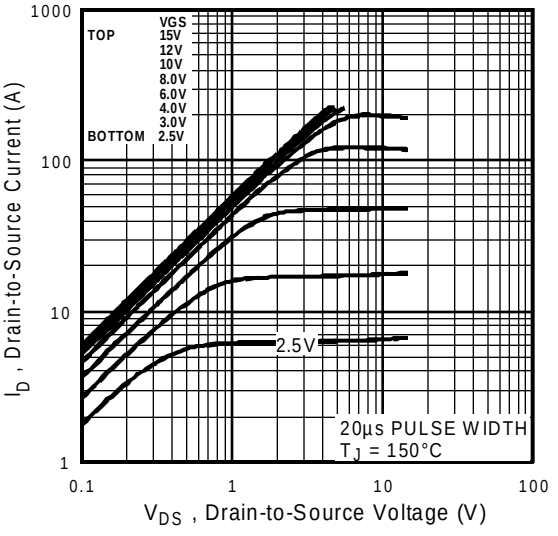


Fig 2. Typical Output Characteristics, $T_J = 150^oC$

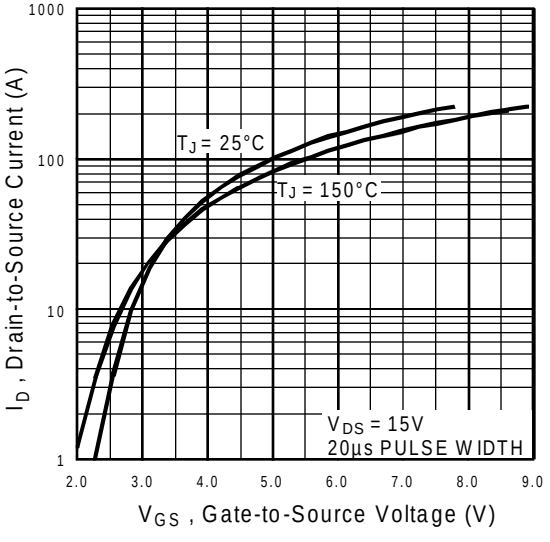


Fig 3. Typical Transfer Characteristics

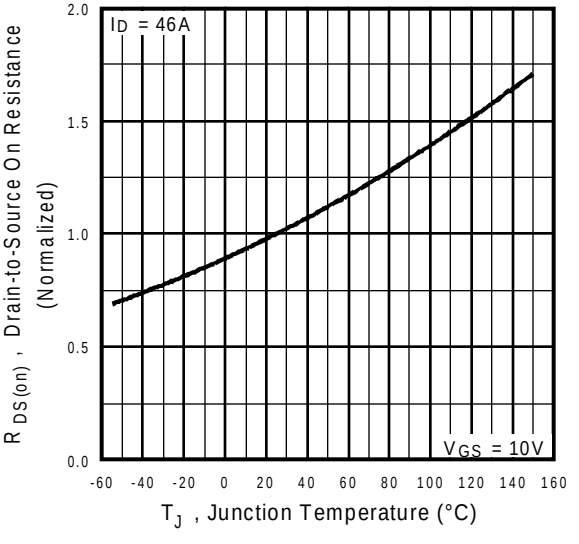


Fig 4. Normalized On-Resistance Vs. Temperature

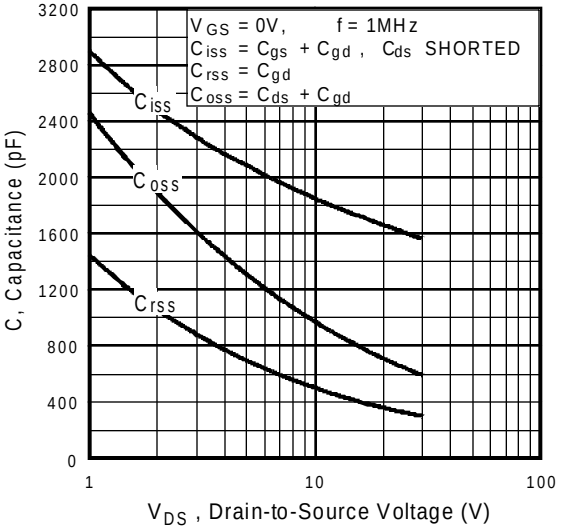


Fig 5. Typical Capacitance Vs. Drain-to-Source Voltage

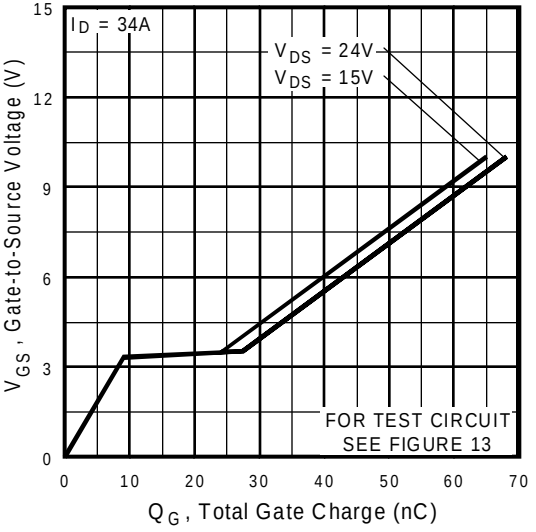


Fig 6. Typical Gate Charge Vs. Gate-to-Source Voltage

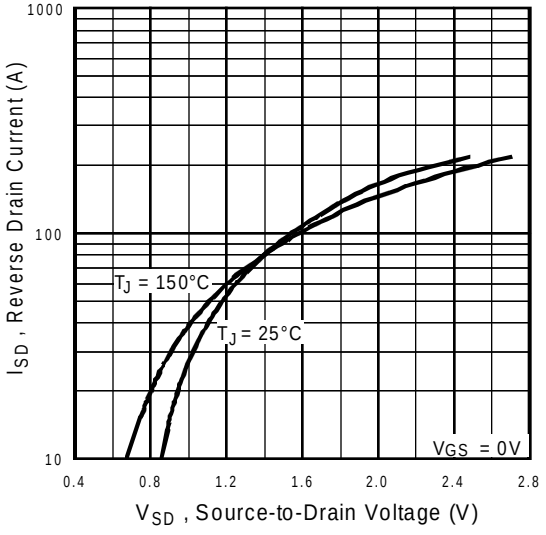


Fig 7. Typical Source-Drain Diode Forward Voltage

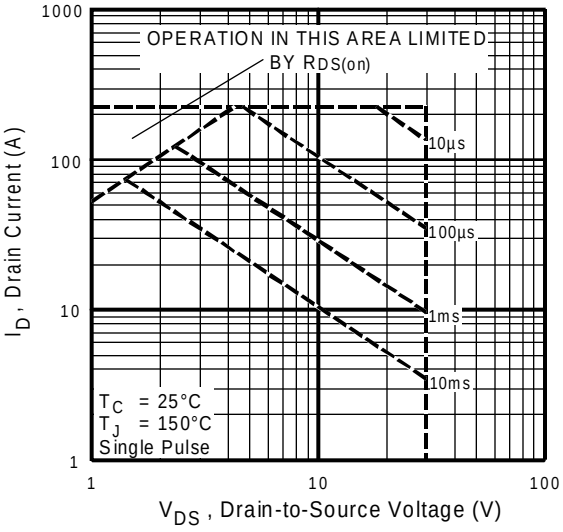


Fig 8. Maximum Safe Operating Area

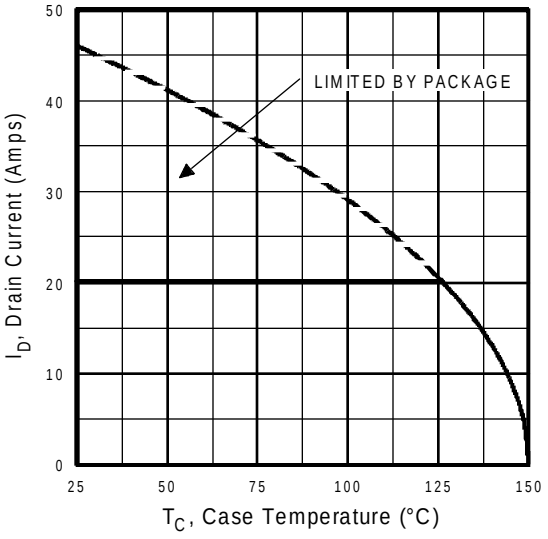


Fig 9. Maximum Drain Current Vs. Case Temperature

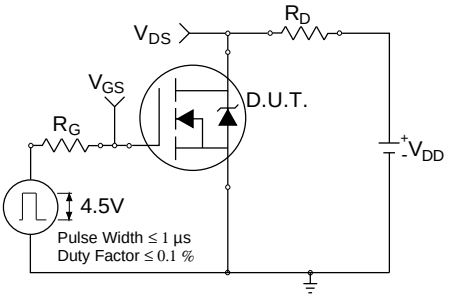


Fig 10a. Switching Time Test Circuit

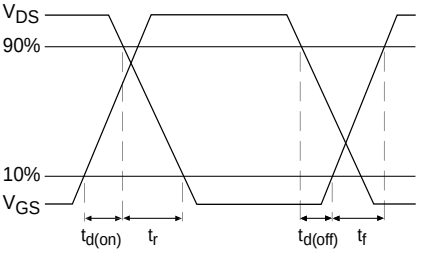


Fig 10b. Switching Time Waveforms

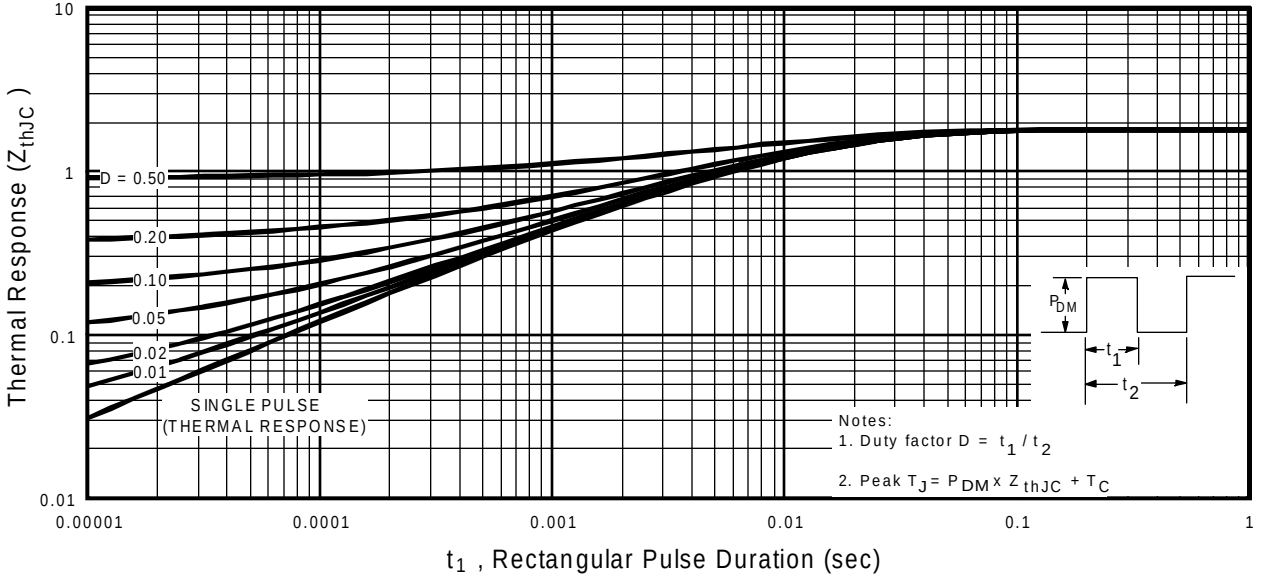


Fig 11. Maximum Effective Transient Thermal Impedance, Junction-to-Case

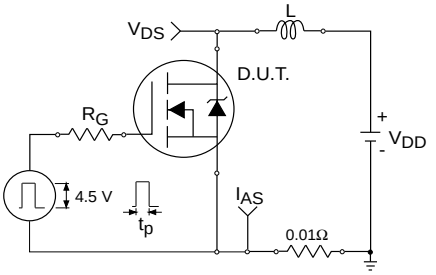


Fig 12a. Unclamped Inductive Test Circuit

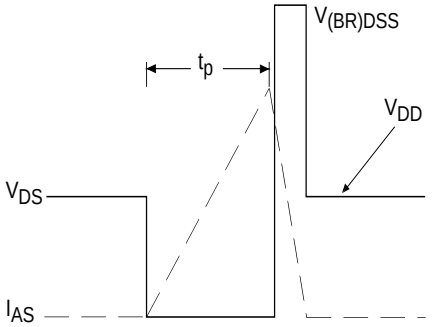


Fig 12b. Unclamped Inductive Waveforms

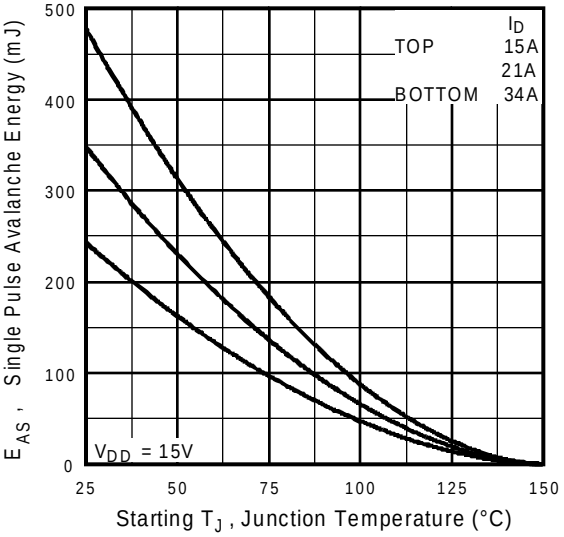


Fig 12c. Maximum Avalanche Energy Vs. Drain Current

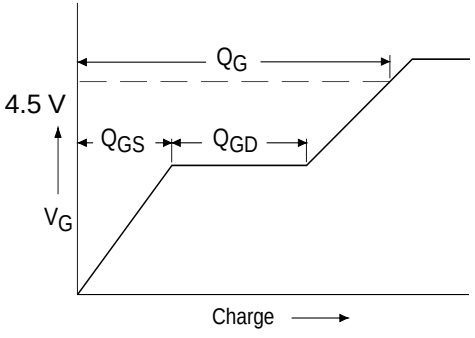


Fig 13a. Basic Gate Charge Waveform

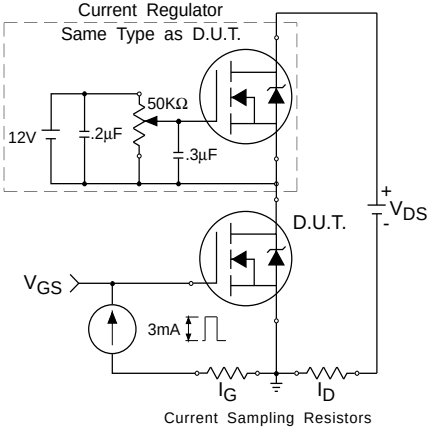
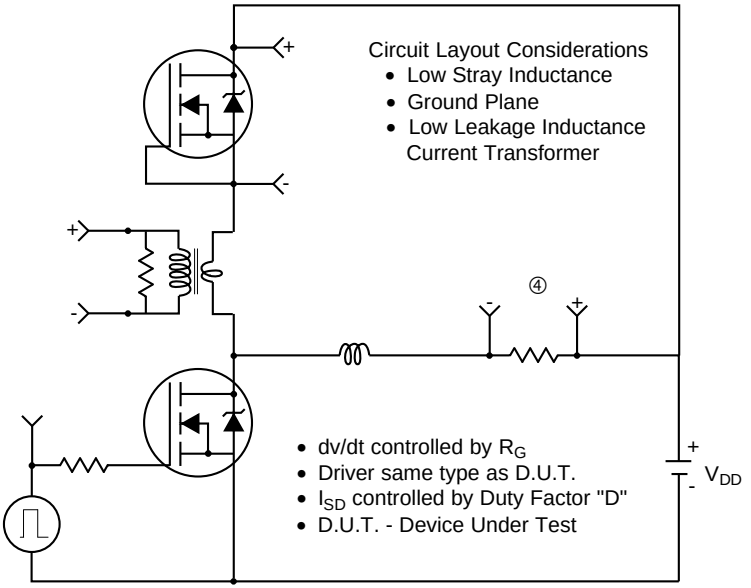
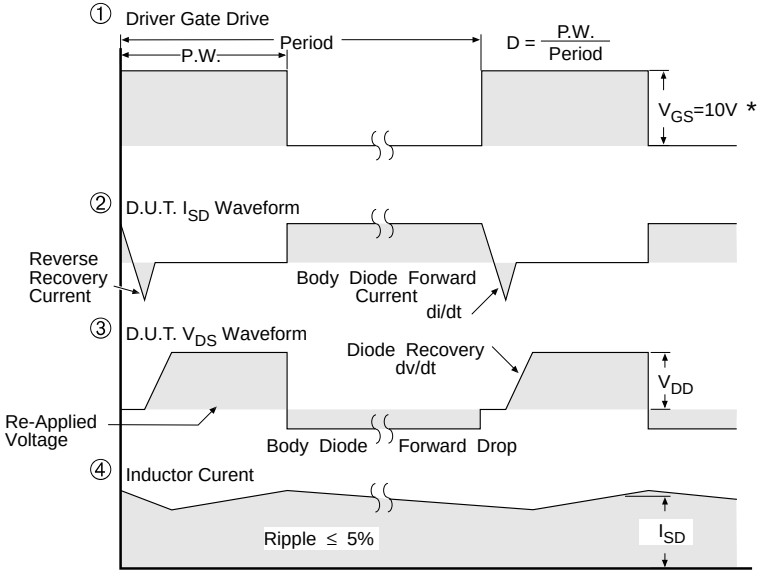


Fig 13b. Gate Charge Test Circuit

Peak Diode Recovery dv/dt Test Circuit



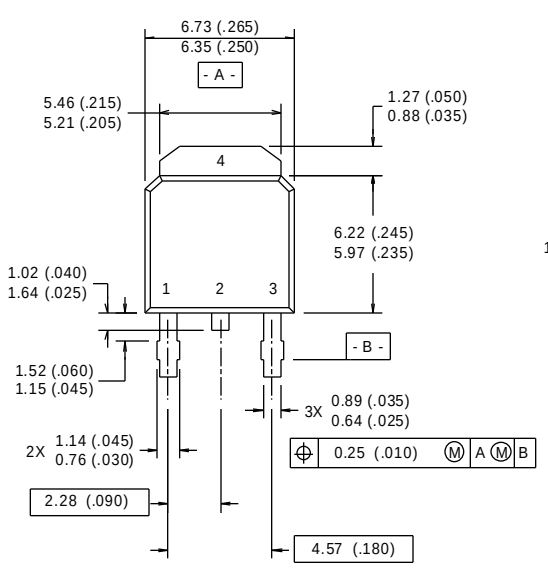


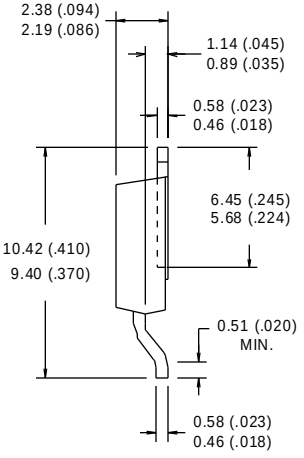
* V_{GS} = 5V for Logic Level Devices

Fig 13. For N-Channel HEXFETS

Package Outline

TO-252AA Outline
Dimensions are shown in millimeters (inches)





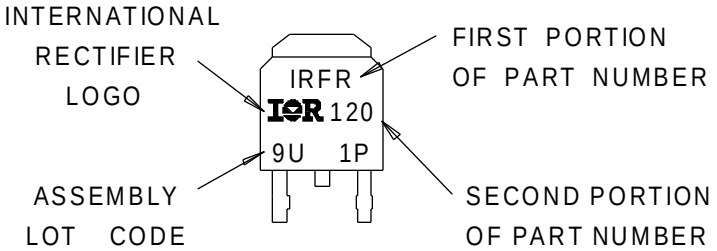
LEAD ASSIGNMENTS
1 - GATE
2 - DRAIN
3 - SOURCE
4 - DRAIN

NOTES:
1 DIMENSIONING & TOLERANCING PER ANSI Y14.5M, 1982.
2 CONTROLLING DIMENSION : INCH.
3 CONFORMS TO JEDEC OUTLINE TO-252AA.
4 DIMENSIONS SHOWN ARE BEFORE SOLDER DIP, SOLDER DIP MAX. +0.16 (.006).

Part Marking Information

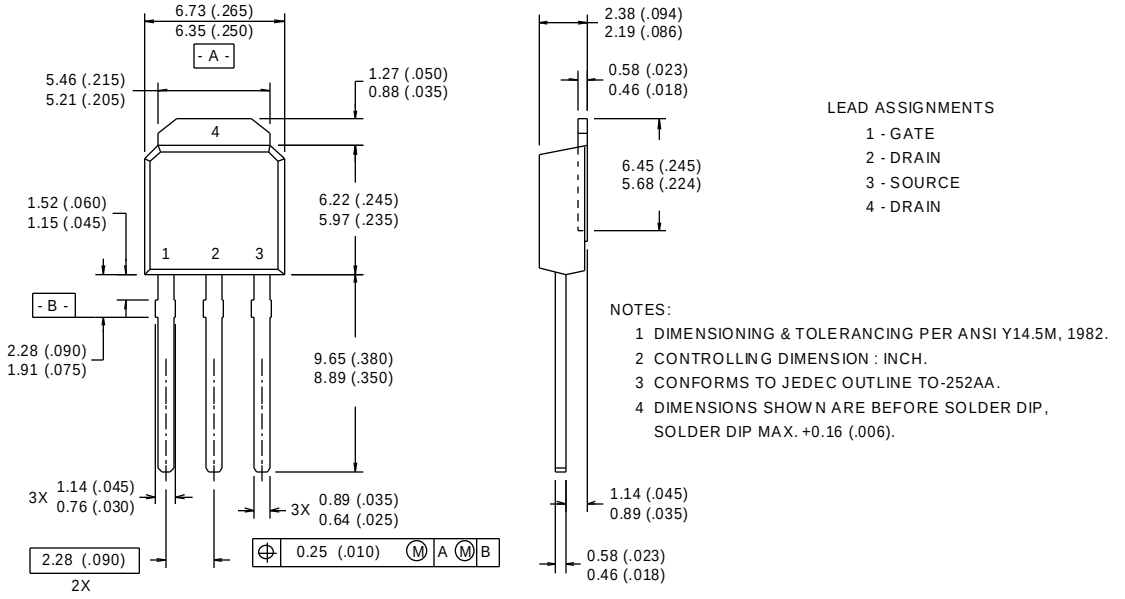
TO-252AA (D-PARK)

EXAMPLE : THIS IS AN IRFR120
WITH ASSEMBLY
LOT CODE 9U1P



Package Outline

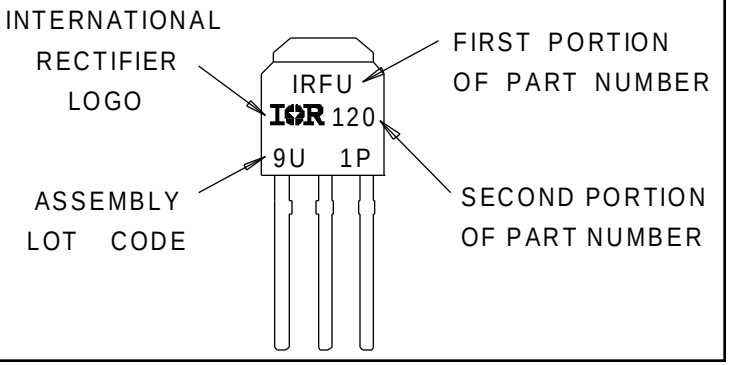
TO-251AA Outline
Dimensions are shown in millimeters (inches)



Part Marking Information

TO-251AA (I-PARK)

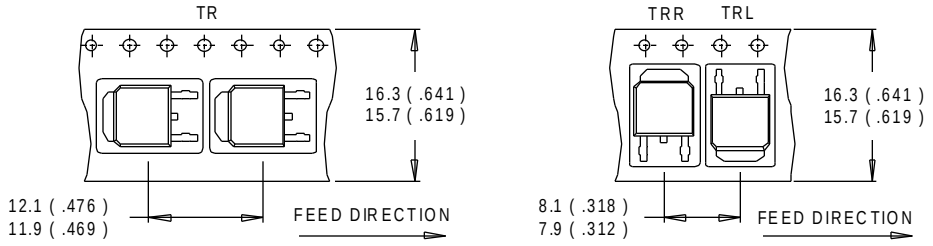
EXAMPLE : THIS IS AN IRFU120
WITH ASSEMBLY
LOT CODE 9U1P



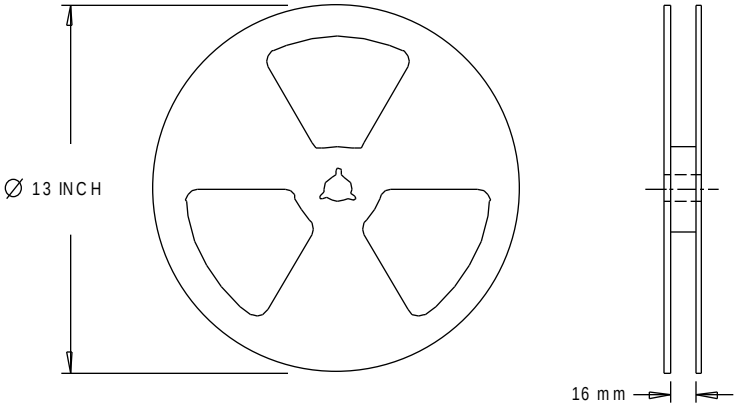
Tape & Reel Information

TO-252AA

Dimensions are shown in millimeters (inches)



NOTES :
1. CONTROLLING DIMENSION : MILLIMETER.
2. ALL DIMENSIONS ARE SHOWN IN MILLIMETERS (INCHES).
3. OUTLINE CONFORMS TO EIA-481 & EIA-541.



NOTES :
1. OUTLINE CONFORMS TO EIA-481.

International
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IR GERMANY: Saalburgstrasse 157, 61350 Bad Homburg Tel: ++ 49 6172 96590
IR ITALY: Via Liguria 49, 10071 Borgaro, Torino Tel: ++ 39 11 451 0111
IR FAR EAST: K&H Bldg., 2F, 3-30-4 Nishi-Ikeburo 3-Chome, Toshima-Ki, Tokyo Japan 171 Tel: 81 3 3983 0086
IR SOUTHEAST ASIA: 315 Outram Road, #10-02 Tan Boon Liat Building, Singapore 0316 Tel: 65 221 8371